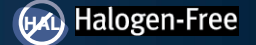


EPC2010C – Enhancement Mode Power Transistor

 V_{DS} , 200 V $R_{DS(on)}$, 25 mΩ I_D , 22 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings

| PARAMETER | | VALUE | UNIT |
|-----------|---|------------|------------------|
| V_{DS} | Drain-to-Source Voltage (Continuous) | 200 | V |
| I_D | Continuous ($T_A = 25^\circ\text{C}$, $R_{\theta JA} = 5.3$) | 22 | A |
| | Pulsed (25°C , $T_{PULSE} = 300 \mu\text{s}$) | 90 | |
| V_{GS} | Gate-to-Source Voltage | 6 | V |
| | Gate-to-Source Voltage | -4 | |
| T_J | Operating Temperature | -40 to 150 | $^\circ\text{C}$ |
| T_{STG} | Storage Temperature | -40 to 150 | |

Thermal Characteristics

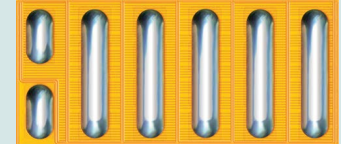
| PARAMETER | | TYP | UNIT |
|-----------------|--|-----|---------------------------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | 1.1 | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JB}$ | Thermal Resistance, Junction-to-Board | 2.7 | |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient (Note 1) | 56 | |

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------|--------------------------------|---|-----|-----|-----|---------------|
| BV_{DSS} | Drain-to-Source Voltage | $V_{GS} = 0 \text{ V}$, $I_D = 200 \mu\text{A}$ | 200 | | | V |
| I_{DSS} | Drain-Source Leakage | $V_{GS} = 0 \text{ V}$, $V_{DS} = 160 \text{ V}$ | | 50 | 150 | μA |
| I_{GSS} | Gate-to-Source Forward Leakage | $V_{GS} = 5 \text{ V}$ | | 1 | 3 | mA |
| | Gate-to-Source Reverse Leakage | $V_{GS} = -4 \text{ V}$ | | 50 | 150 | μA |
| $V_{GS(TH)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}$, $I_D = 3 \text{ mA}$ | 0.8 | 1.4 | 2.5 | V |
| $R_{DS(on)}$ | Drain-Source On Resistance | $V_{GS} = 5 \text{ V}$, $I_D = 12 \text{ A}$ | | 18 | 25 | mΩ |
| V_{SD} | Source-Drain Forward Voltage | $I_S = 0.5 \text{ A}$, $V_{GS} = 0 \text{ V}$ | | 1.7 | | V |

All measurements were done with substrate connected to source.



EPC2010C eGaN® FETs are supplied only in passivated die form with solder bars

Applications

- High Speed DC-DC conversion
- Class D Audio
- Lidar

Benefits

- Ultra High Efficiency
- Ultra Low $R_{DS(on)}$
- Ultra Low Q_G
- Ultra Small Footprint

Dynamic Characteristics ($T_j = 25^\circ\text{C}$ unless otherwise stated)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-------------|------------------------------|---|-----|-----|-----|----------|
| C_{ISS} | Input Capacitance | $V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$ | | 380 | 540 | pF |
| C_{OSS} | Output Capacitance | | | 240 | 320 | |
| C_{RSS} | Reverse Transfer Capacitance | | | 1.8 | 2.7 | |
| R_G | Gate Resistance | | 0.4 | | | Ω |
| Q_G | Total Gate Charge | $V_{DS} = 100\text{ V}, I_D = 12\text{ A}, V_{GS} = 5\text{ V}$ | | 3.7 | 5.3 | nC |
| Q_{GS} | Gate-to-Source Charge | $V_{DS} = 100\text{ V}, I_D = 12\text{ A}$ | | 1.3 | | |
| Q_{GD} | Gate-to-Drain Charge | | | 0.7 | 1.3 | |
| $Q_{G(TH)}$ | Gate Charge at Threshold | | | 0.9 | | |
| Q_{OSS} | Output Charge | $V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$ | | 40 | 52 | |
| Q_{RR} | Source-Drain Recovery Charge | | | 0 | | |

All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Figure 1: Typical Output Characteristics at 25°C

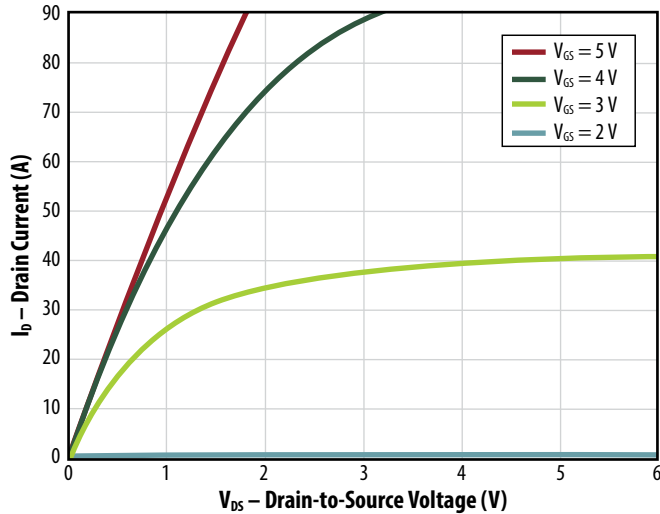


Figure 2: Transfer Characteristics

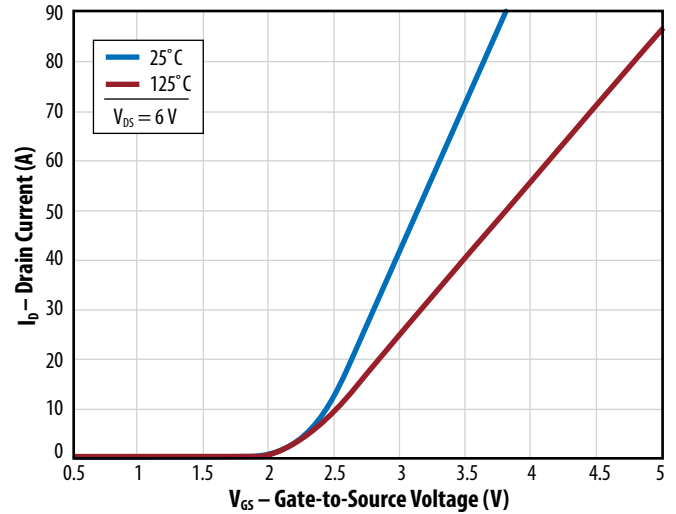


Figure 3: $R_{DS(on)}$ vs. V_{GS} for Various Drain Current

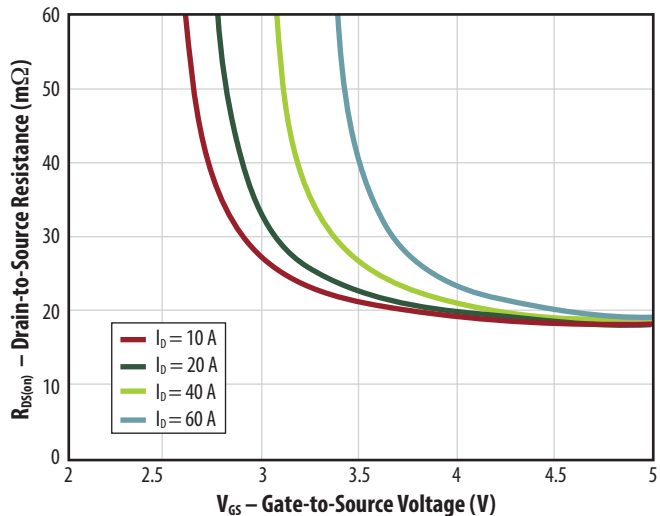


Figure 4: $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

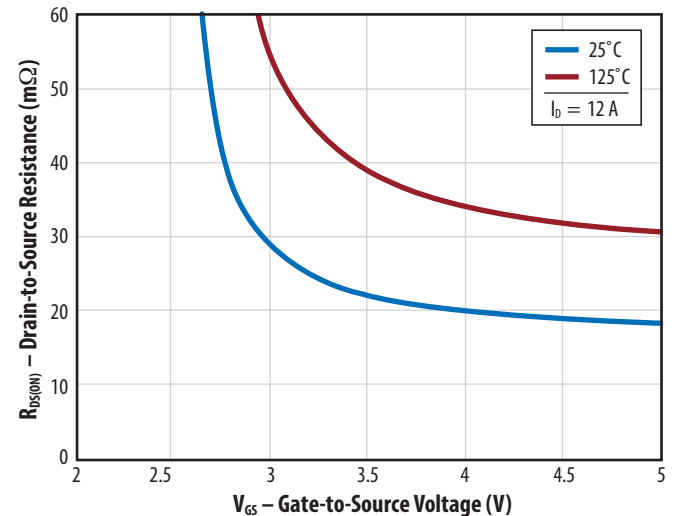


Figure 5a: Capacitance Linear Scale

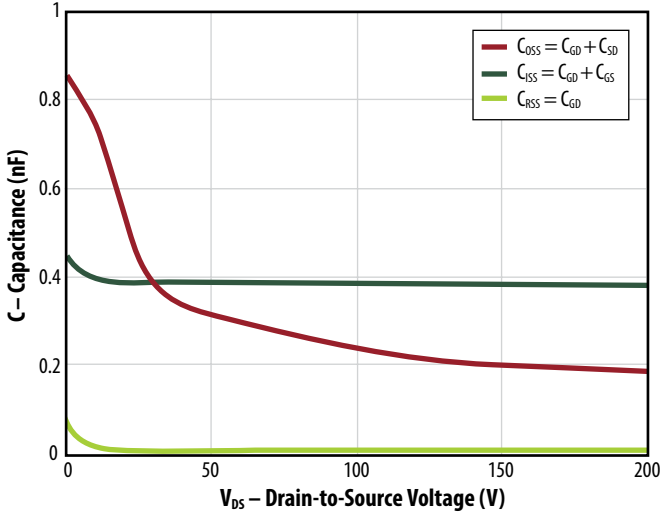


Figure 5b: Capacitance Log Scale

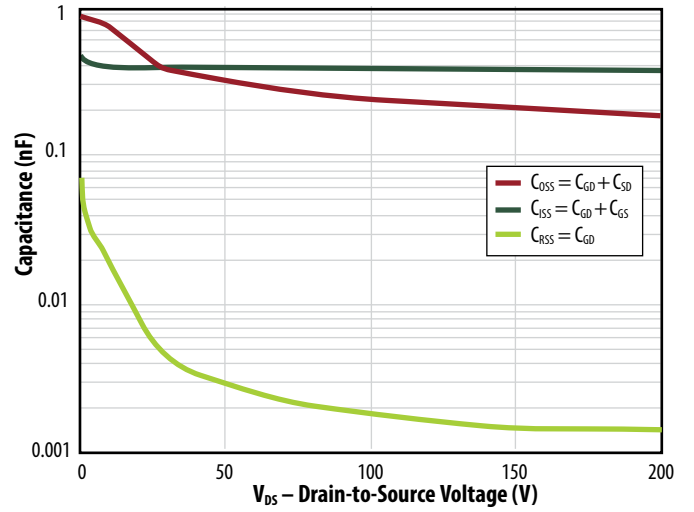


Figure 6: Gate Charge

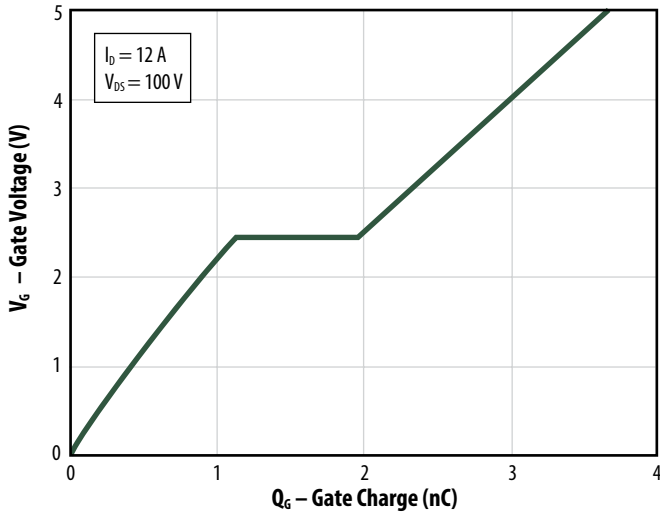


Figure 7: Reverse Drain-Source Characteristics

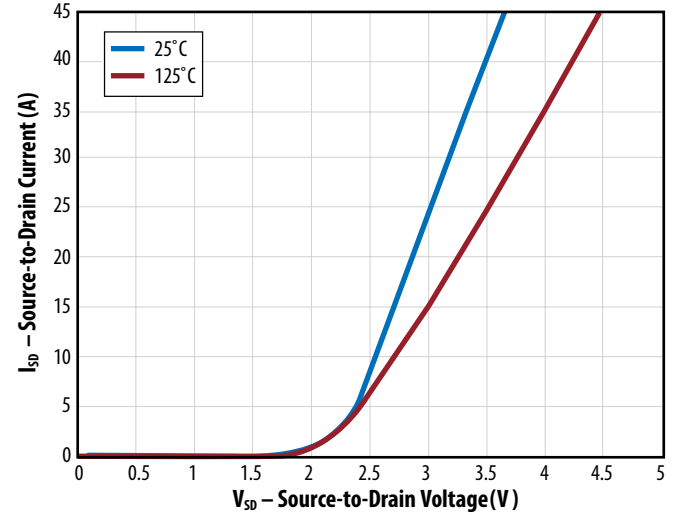


Figure 8: Normalized On Resistance vs. Temperature

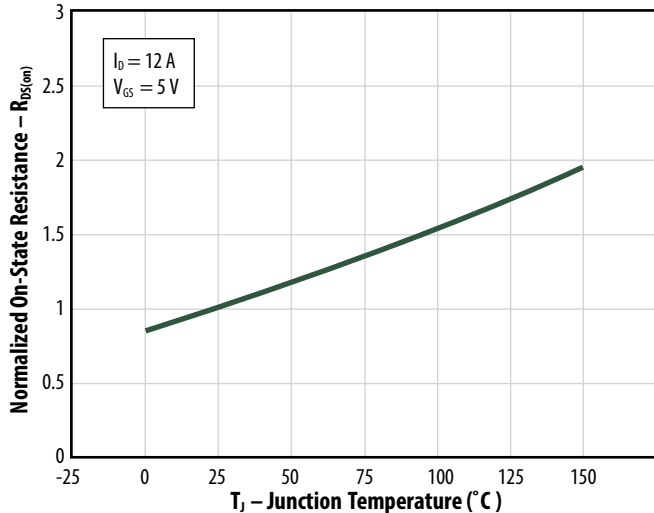


Figure 9: Normalized Threshold Voltage vs. Temperature

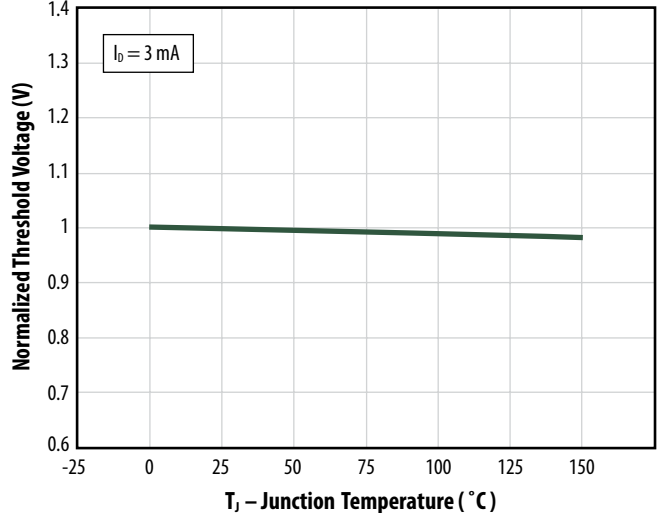


Figure 10: Gate Current

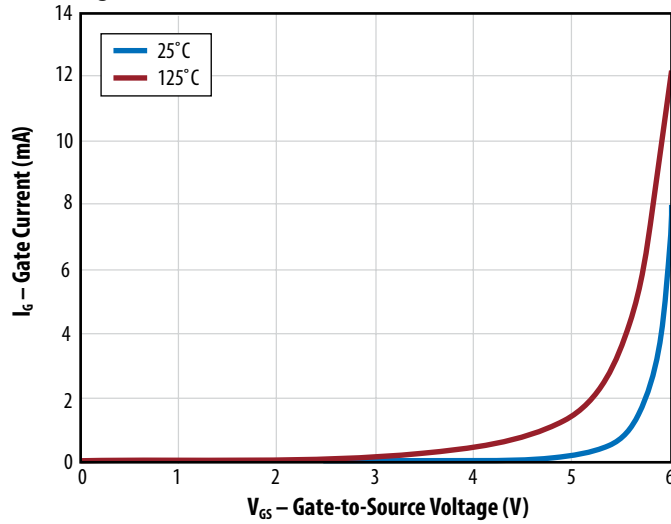


Figure 11: Transient Thermal Response Curves

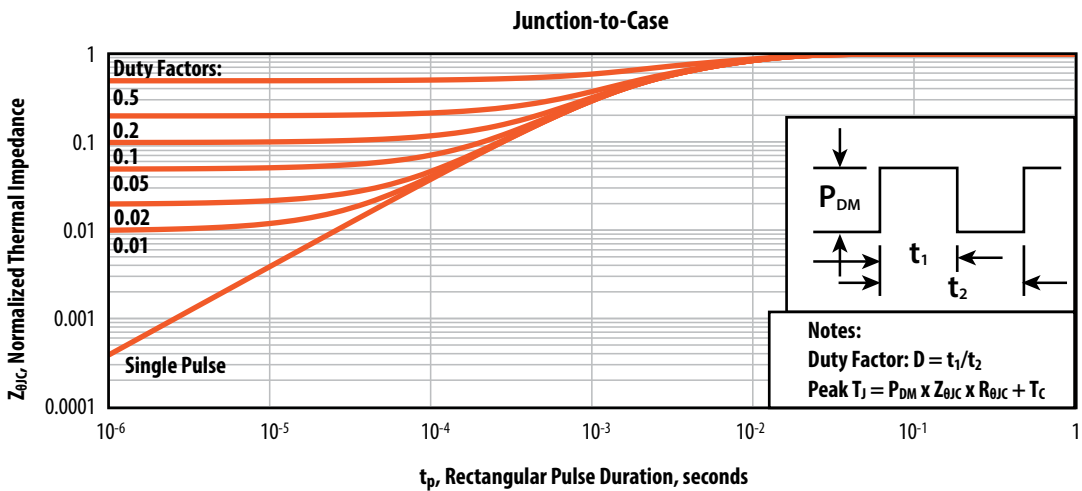
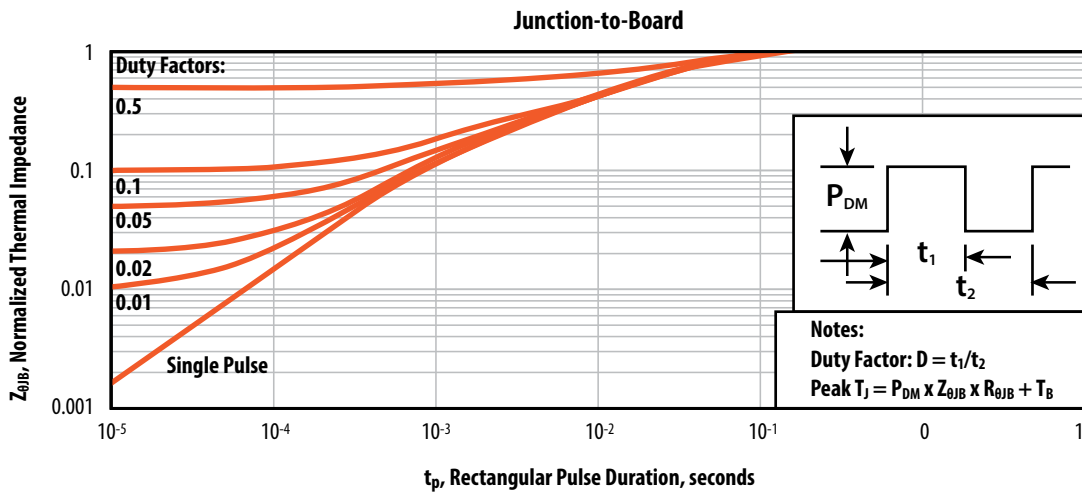
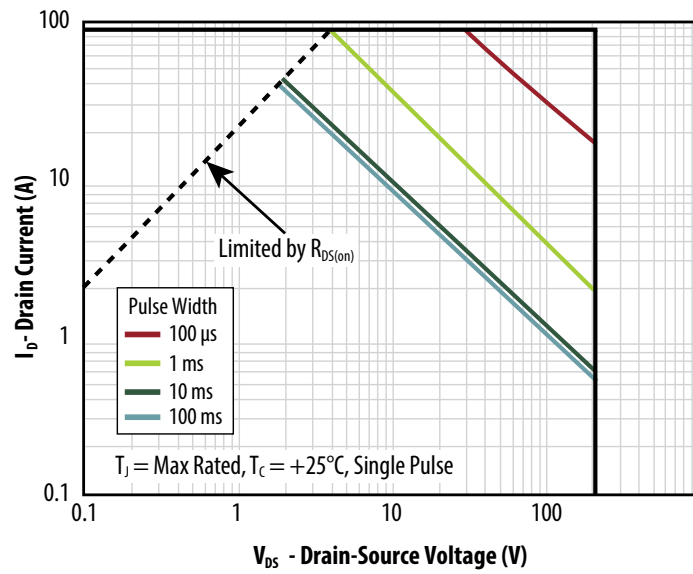
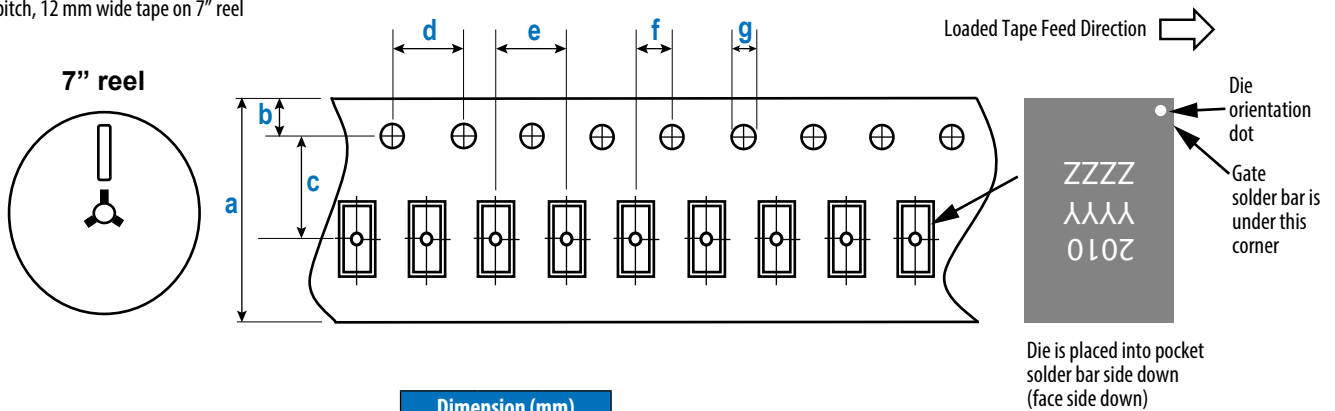


Figure 12: Safe Operating Area



TAPE AND REEL CONFIGURATION

4 mm pitch, 12 mm wide tape on 7" reel

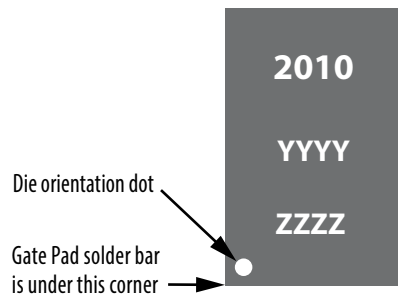


| EPC2010 (Note 1) | Dimension (mm) | | |
|------------------|----------------|-------|-------|
| | Target | MIN | MAX |
| a | 12.00 | 11.90 | 12.30 |
| b | 1.75 | 1.65 | 1.85 |
| c (Note 2) | 5.50 | 5.45 | 5.55 |
| d | 4.00 | 3.90 | 4.10 |
| e | 4.00 | 3.90 | 4.10 |
| f (Note 2) | 2.00 | 1.95 | 2.05 |
| g | 1.50 | 1.50 | 1.60 |

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

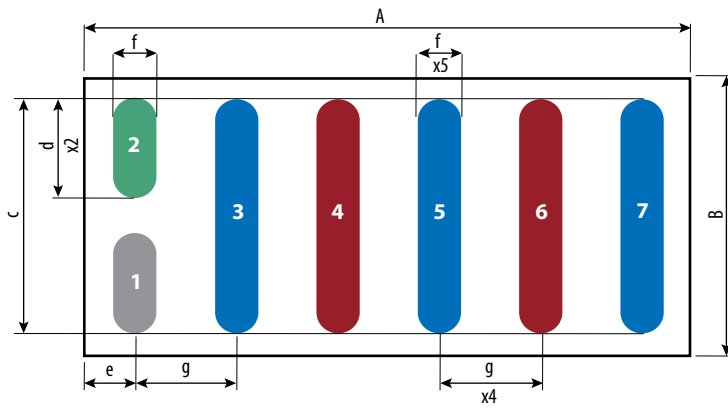
DIE MARKINGS



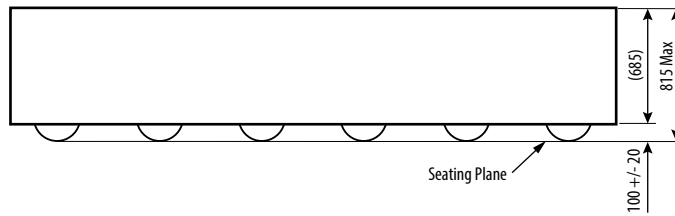
| Part Number | Laser Markings | | |
|-------------|-----------------------|------------------------------|------------------------------|
| | Part # Marking Line 1 | Lot_Date Code Marking Line 2 | Lot_Date Code Marking Line 3 |
| EPC2010C | 2010 | YYYY | ZZZZ |

DIE OUTLINE

Solder Bar View



Side View



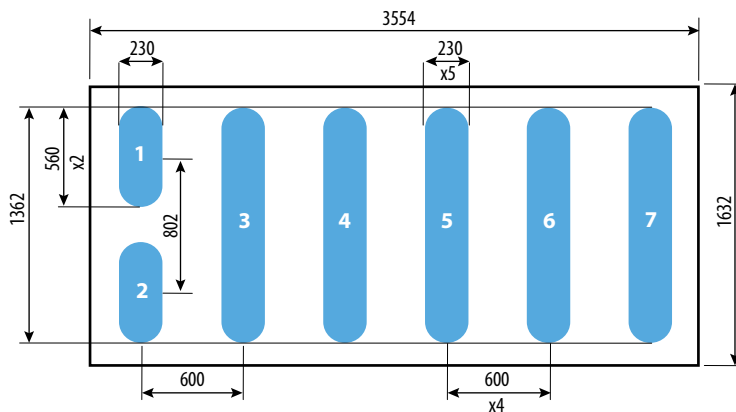
| DIM | MICROMETERS | | |
|-----|-------------|---------|------|
| | MIN | Nominal | MAX |
| A | 3524 | 3554 | 3584 |
| B | 1602 | 1632 | 1662 |
| c | 1379 | 1382 | 1385 |
| d | 577 | 580 | 583 |
| e | 262 | 277 | 292 |
| f | 245 | 250 | 255 |
| g | 600 | 600 | 600 |

Pad no. 1 is Gate;
 Pads no. 3, 5, 7 are Drain;
 Pads no. 4, 6 are Source;
 Pad no. 2 is Substrate.*

*Substrate pin should be connected to Source

RECOMMENDED LAND PATTERN

(units in μm)



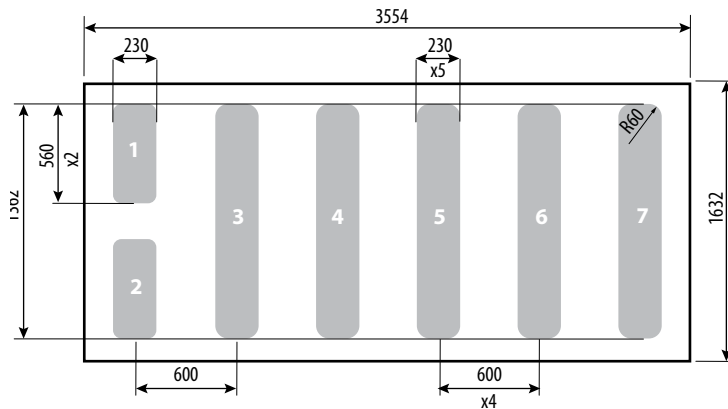
The land pattern is solder mask defined.

Pad no. 1 is Gate;
 Pads no. 3, 5, 7 are Drain;
 Pads no. 4, 6 are Source;
 Pad no. 2 is Substrate.*

*Substrate pin should be connected to Source

RECOMMENDED STENCIL DRAWING

(units in μm)



Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, opening per drawing. The corner has a radius of R60.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at <https://www.epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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